


<b>Search Notes</b> 	<b>Application/Control No.</b> 10802735	<b>Applicant(s)/Patent Under Reexamination</b> TAKAFUJI ET AL.
	<b>Examiner</b> Tran, Thien F	<b>Art Unit</b> 2811

SEARCHED			
Class	Subclass	Date	Examiner
257	59, 64, 66, 69, 70, 72, 347	12/21/06	TT
257	347-354, 507	03/15/07	TT

SEARCH NOTES		
Search Notes	Date	Examiner
Interference search history printout	03/15/07	TT

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner